



CLUSTER DETECTOR TEST REPORT

CLUSTER DETECTOR No. 3

Test carried on 08.12.11 – 09.12.11

Ch.	HEX	U _{op} [V]	U _{op} – 500 V		U _{op}			
			FWHM [keV]	$\frac{FWTM}{FWHM}$	1332 keV			122 keV
					FWHM [keV]	$\frac{FWTM}{FWHM}$	Pos. [Ch.]	FWHM [keV]
A	72	4000	2.06	n.c.	2.03	n.c.	6434	
B	110	4000	2.05	n.c.	1.95	n.c.	6728	
C	108	4500	2.21	n.c.	2.18	n.c.	6740	
D	66	4000	2.15	n.c.	2.06	n.c.	6145	
E	91	4500	2.01	n.c.	1.97	n.c.	9038	
F	65	4000	2.10	n.c.	1.99	n.c.	6710	
G	60	3500	2.09	n.c.	2.04	n.c.	6769	

Operational Temperature: -156.0 °C

Date: 09.12.2011

Tested by:
/I.Kojouharov/

Assembly and test remarks:

Regular test after assembly at RIKEN. Ch.E – tested at gain 100x10.2 and recalculated.

Test Equipment:

HV – ORTEC 660

Main Amplifier – ORTEC 671, $\tau = 6 \mu\text{s}$, Gain 100 x 0.72

ADC – 4801A (RIKEN), MCA - PC98B

Source - ^{60}Co